

CORRECTION

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The authors would like to make the following corrections to their published article:

- (1) On page 8627, left column, sentence beginning “For further confirmation. . .”, the formula $\text{Bi}_{1.84}\text{Cr}_{0.16}\text{Se}_3$ should be replaced with $\text{Bi}_{1.78}\text{Cr}_{0.22}\text{Se}_3$ so that the amended sentence reads “For further confirmation, we simulate the electron doping effect by growing extra Cr metal on the surface of $\text{Bi}_{1.78}\text{Cr}_{0.22}\text{Se}_3$ (Fig. 6).”
- (2) In Fig. 4, Bi_2Se_3 should be replaced with $\text{Bi}_{1.84}\text{Cr}_{0.16}\text{Se}_3$ as shown in the amended figure below:

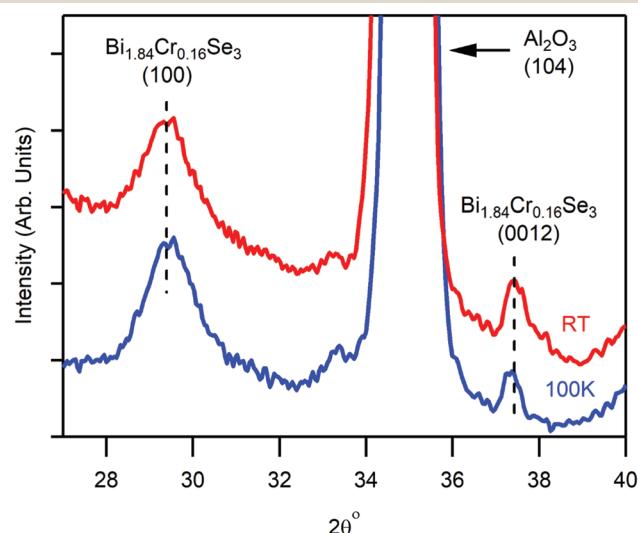


Fig. 4 X-ray diffraction patterns obtained RT (red) and 100 K (blue) for $\text{Bi}_{1.84}\text{Cr}_{0.16}\text{Se}_3$ films grown on $\text{Al}_2\text{O}_3(0001)$ substrates. Data were collected with $\text{Cu K}\alpha$ radiation ($\lambda = 1.5418 \text{ \AA}$). Dashed lines are for guiding the eyes.

The Royal Society of Chemistry apologises for these errors and any consequent inconvenience to authors and readers.

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